## Notice of References Cited

Application/Control No. 10/042,652	Applicant(s)/Patent Under Reexamination LOTSPIECH ET AL.		
Examiner	Art Unit		
Aubrey H. Berger	2134	Page 1 of 1	

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,691,149	02-2004	Yokota et al.	709/201
	В	US-2001/0029581	10-2001	Knauft, Christopher L.	713/193
	С	US-2002/0083319	06-2002	ISHIGURO et al.	713/168
	D	US-6,690,795	02-2004	Richards, William James	380/203
	E	US-6,684,331	01-2004	Srivastava, Sunil K.	713/163
	F	US-6,397,329	05-2002	Aiello et al.	713/155
	G	US-2002/0174366	11-2002	Peterka et al.	713/201
	Н	US-6,839,436	01-2005	Garay et al.	380/278
	ı	US-2003/0051151	03-2003	Asano et al.	713/193
	J	US-2005/0198679	09-2005	Baran et al.	725/088
	K	US-2005/0131832	06-2005	Fransdonk, Robert W.	705/059
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*	-	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Q					
	R					
	S					
	Т			-		

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Bruce Schneier, Applied Cyrtography, 1996, John Wiley & Sons, 2 <sup>nd</sup> ed., page 270
	V	
	8	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.